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JAPANESE PATENT OFFICE

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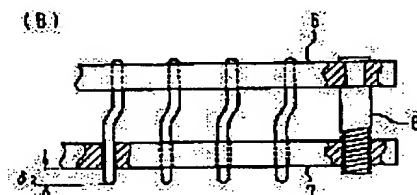
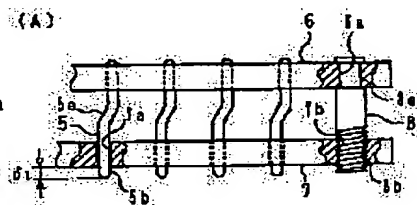
MIZUTA MASA HARU

(54) PERPENDICULAR TYPE PROBE CARD DEVICE

(57)Abstract:

PROBLEM TO BE SOLVED: To provide a perpendicular type probe card device that can effectively and easily polish and clean the tip of a probe needle.

SOLUTION: This perpendicular type probe device comprises an upper guide plate 6, a lower guide plate 7 which is spacedly opposed to the upper guide plate 6 and in which a plurality of guide holes 7a are formed at specified positions, a plurality of probe needles 5 whose upper ends are stuck to the upper guide plate 6 and the lower ends are projected specified length through the guide holes 7a of the lower guide plate 7, and a guide plate position adjusting means 8, which intervenes between both guide plates 6 and 7 and is formed to be able to set the distance between both guide plates to a specified value.



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